 earch No	

Application/Control No.	rol No. Applicant(s)/Patent under Reexamination	
09/938,550	YANO ET AL.	
Examiner	Art Unit	
Yasin M. Barqadle	2153	

	SEAR	CHED	
Class	Subclass	Date	Examiner
709	204-207	6/8/2006	YB

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
<u> </u>			

(INCLUDING SEARCH		
	DATE	EXMR
East (US Patent, PG PUB, EPO, JPO and Derwent)	6/8/2006	ΥВ